

An image analysis approach for the structural characterization of pyrocarbons

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Abstract

We focus on the nanometric structure of pyrocarbons obtained by Chemical Vapor Infiltration and observed by High Resolution Transmission Electron Microscopy (HRTEM) imaging. More particularly, we present an automated approach to the quantitative description of fringe lengths and we propose a simple stochastic model for fringe description which corroborates the obtained length statistical distributions.



The Fringe Extraction Algorithm



Directional filtering in the frequency domain

Detection of fringe endings



curve tracking

Da Costa, Germain, Baylou, "Level curve algorithm for textural feature extraction", Proc. of ICPR 2000, pp. 921-924. Da Costa, Germain, Baylou, "A curvilinear approach for textural feature extraction", Proc. of QCAV 2001. **Fringe Length Statistics**

Fringe length statistics have been computed on 4 image sets: 2 fabrication processes, 2 thermal treatments.



Results

- distributions characterized by one mode and an exponential decrease,
- the position of the mode and the speed of decrease depend on the material and on the thermal treatment,
- the effect of thermal treatment is clearly shown,
- differences between 2 processes vanish with thermal treatment.

Towards a stochastic model for structure description

A simple model:

- fringes described individually;
- a distorted fringe (L_2) is an arrangement of straight segments (L_1) ,
- a straight segment (L_1) is made of aligned elementary segments (L_0) ,
- cohesion between 2 elementary segments: probability p₁,
- cohesion between 2 straight segments: probability p2,
- L₀ follows a normal distribution $\mathcal{N}(I_0, \sigma_0^2)$.



